

Appl. No. 10/761,825  
Response dated Aug. 4, 2005  
Reply to Office action of July 8, 2005

**Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

1-27. (cancelled)

28. (previously presented) A probe-comb apparatus comprising:

a two-metal probe-needle having a first tip-end and a second end; a film segment having a second surface and a first surface to which the probe-needle is attached and wherein the tip-end extends beyond an edge of the film.

29. (previously presented) The apparatus in claim 28 wherein said tip-end comprises a noble metal.

30. (previously presented) The apparatus in claim 29 wherein said noble metal is selected from the group consisting of palladium, rhodium, and gold.

31. (previously presented) The apparatus in claim 29 wherein said tip-end comprises a metal and a noble metal deposited thereon.

32. (previously presented) The apparatus in claim 28 wherein said tip-end is between 0.00075 and 0.0015 inches thick.

33. (previously presented) The apparatus in claim 28 wherein said tip-end is at least 0.05 inches long.

34. (previously presented) The apparatus in claim 28 wherein tip-end is between 0.00075 and 0.002 inches wide.

35. (previously presented) The apparatus in claim 28 wherein a second probe-needle is attached on the film segment.

36. (previously presented) The apparatus in claim 28 wherein said film is a thermally stable, dielectric, polymeric material.

TI-30810A - 2

Appl. No. 10/761,825

Response dated Aug. 4, 2005

Reply to Office action of July 8, 2005

37. (previously presented) The apparatus in claim 28 wherein said film is between 0.001 and 0.003 inches thick.

38. (previously presented) The apparatus in claim 28 wherein said film comprises polyimide.

39. (previously presented) The apparatus in claim 28 wherein said probe-needle is formed to optimize its electrical impedance.

40. (previously presented) The apparatus in claim 28 further including a ground plane patterned on the second surface of said film.

41. (previously presented) The apparatus in claim 28 wherein the probe-needle is patterned with the aid of a computer and is formed by a laser.

42. (previously presented) The apparatus in claim 28 wherein the probe-needle is at least partially formed by laser ablation.

43-49. (canceled)